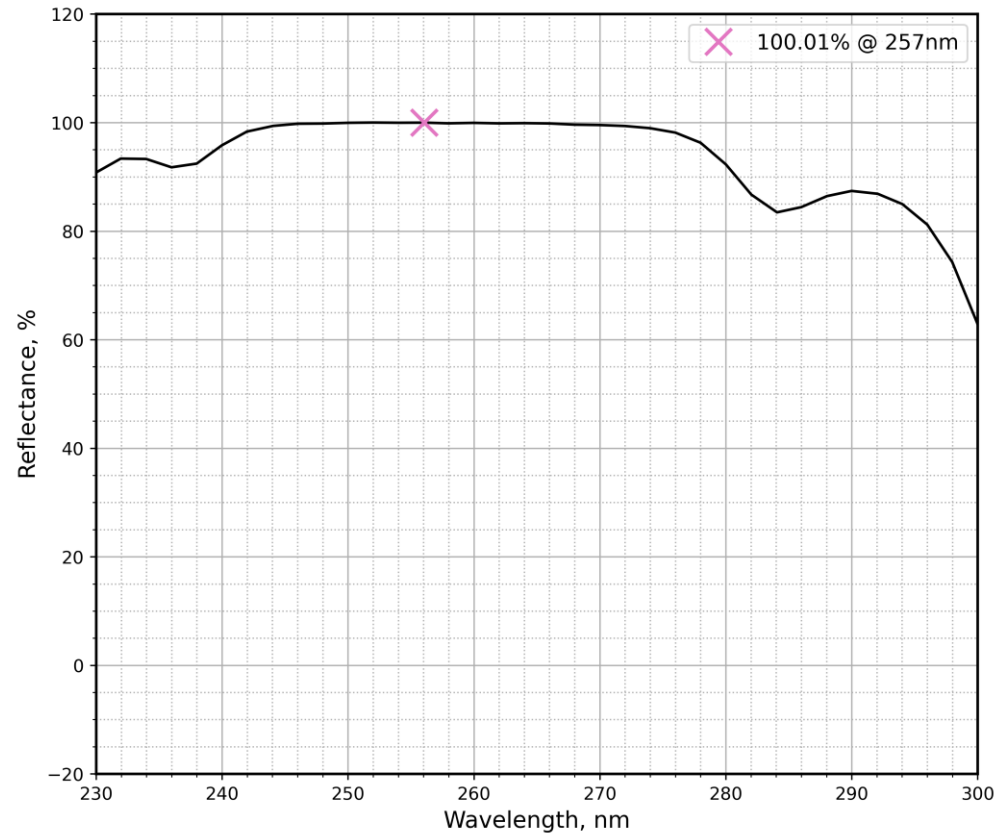


S1: HRs>99.5% @ 257 nm + HTP>99% @ 515 + 1030 nm, AOI=45°
S2: Arp<0.1% @515+1030 nm, AOI=45°



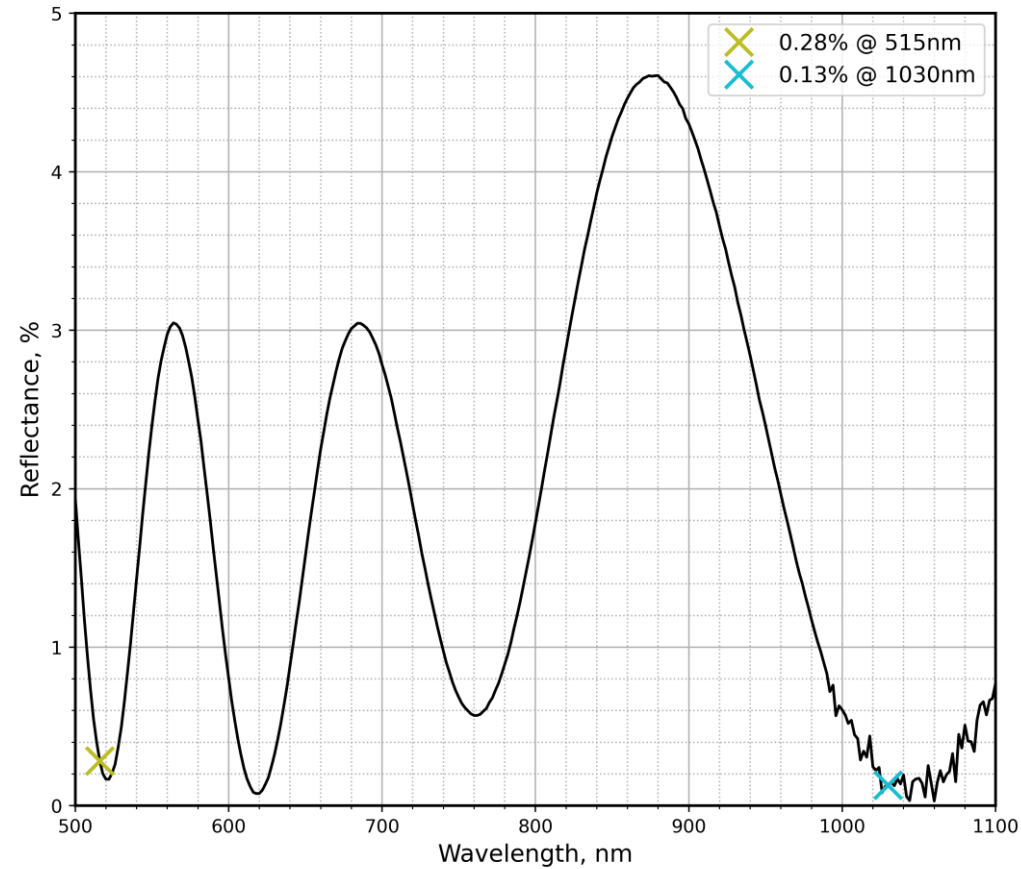
PO3364 Rs S1

Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1: HRs>99.5% @ 257 nm + HTP>99% @ 515 + 1030 nm, AOI=45°
S2: ARp<0.1% @ 515 + 1030 nm, AOI=45°



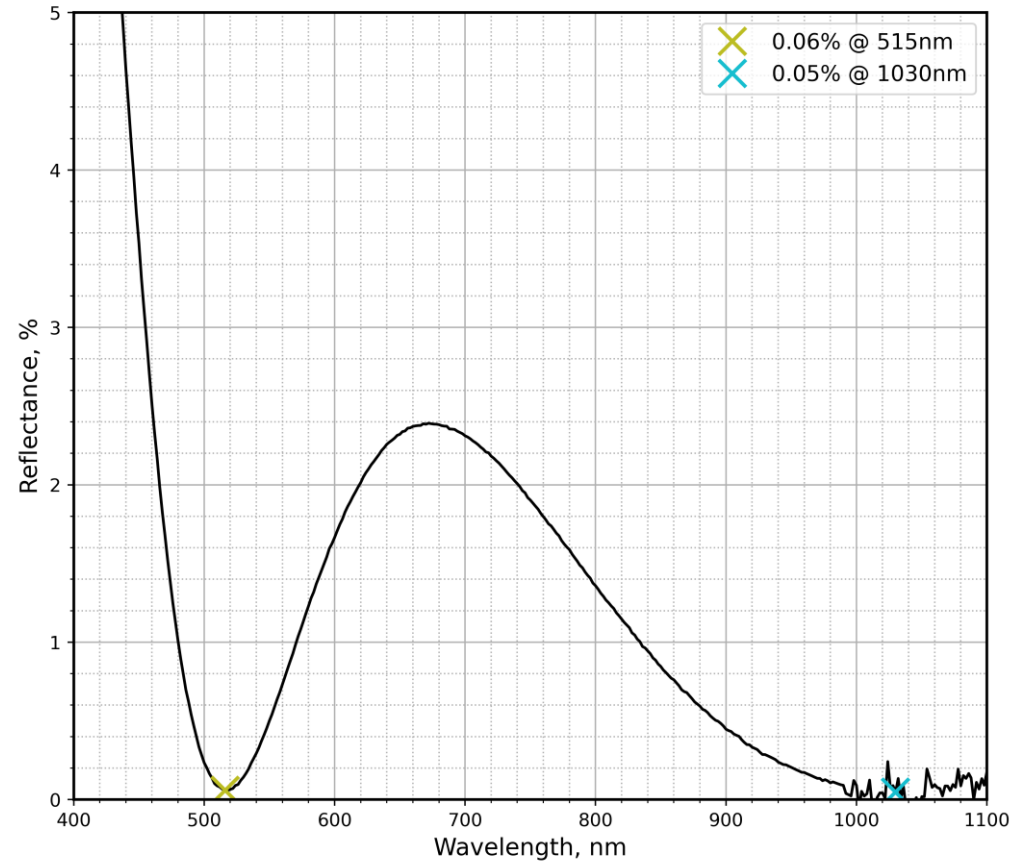
PO3364 Rp i45 S1

Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

S1: HRs>99.5% @ 257 nm + HTp>99% @ 515 + 1030 nm, AOI=45°
S2: ARp<0.1% @ 515 + 1030 nm, AOI=45°



PO3364 Rp i45 S2

Fig. 3.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%